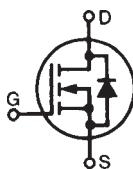


**HiPerFET™ Power MOSFETs**
**Single Die MOSFET**

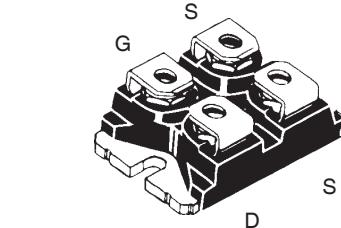
N-Channel Enhancement Mode  
Avalanche Rated, High dv/dt, Low  $t_{rr}$   
Fast Intrinsic Diode


**IXFN25N90**  
**IXFN26N90**

$V_{DSS}$	$I_{D25}$	$R_{DS(on)}$
900V	25A	330mΩ
900V	26A	300mΩ

Symbol	Test Conditions	Maximum Ratings		
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	900		V
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ , $R_{GS} = 1\text{M}\Omega$	900		V
$V_{GSS}$	Continuous	$\pm 20$		V
$V_{GSM}$	Transient	$\pm 30$		V
$I_{D25}$	$T_c = 25^\circ\text{C}$	25N90	25	A
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	25N90	100	A
$I_{D25}$	$T_c = 25^\circ\text{C}$	26N90	26	A
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	26N90	104	A
$I_{AR}$	$T_c = 25^\circ\text{C}$	25N90	25	A
$I_{AR}$	$T_c = 25^\circ\text{C}$	26N90	26	A
$E_{AR}$	$T_c = 25^\circ\text{C}$		64	mJ
$E_{AS}$	$T_c = 25^\circ\text{C}$		3	J
$dV/dt$	$I_s \leq I_{DM}$ , $V_{DD} \leq V_{DSS}$ , $T_J \leq 150^\circ\text{C}$	5		V/ns
$P_D$	$T_c = 25^\circ\text{C}$	600		W
$T_J$		-55 ... +150		°C
$T_{JM}$		150		°C
$T_{stg}$		-55 ... +150		°C
$T_L$	1.6mm (0.062 in.) from case for 10s	300		°C
$V_{ISOL}$	50/60 Hz, RMS	t = 1min	2500	V~
	$I_{ISOL} \leq 1\text{mA}$	t = 1s	3000	V~
$M_d$	Mounting torque	1.5/13		Nm/lb.in.
	Terminal connection torque	1.3/11.5		Nm/lb.in.
<b>Weight</b>		30		g

Symbol	Test Conditions	Characteristic Values		
		( $T_J = 25^\circ\text{C}$ unless otherwise specified)	Min.	Typ.
$BV_{DSS}$	$V_{GS} = 0\text{V}$ , $I_D = 3\text{mA}$	900		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 8\text{mA}$	3.0		5.0 V
$I_{GSS}$	$V_{GS} = \pm 20\text{V}$ , $V_{DS} = 0\text{V}$		$\pm 200$	nA
$I_{DSS}$	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0\text{V}$	$T_J = 125^\circ\text{C}$	100	$\mu\text{A}$
			2	mA
$R_{DS(on)}$	$V_{GS} = 10\text{V}$ , $I_D = 0.5 \cdot I_{D25}$ , Note 1	25N90 26N90		330 mΩ
				300 mΩ

**miniBLOC, SOT-227**


G = Gate      D = Drain  
S = Source

Either Source terminal S can be used as the Source terminal or the Kelvin Source (gate return) terminal.

**Features**

- International standard package
- miniBLOC, with Aluminium nitride isolation
- Low  $R_{DS(ON)}$  HDMOS™ process
- Avalanche Rated
- Low package inductance
- Fast intrinsic diode

**Advantages**

- Low gate drive requirement
- High power density

**Applications:**

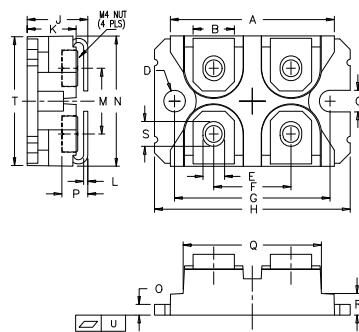
- Switched-mode and resonant-mode power supplies
- DC-DC Converters
- Battery chargers
- DC choppers
- Temperature & lighting controls

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ unless otherwise specified)		Characteristic Values		
			Min.	Typ.	Max.
$g_{fs}$	$V_{DS} = 10\text{V}$ , $I_D = 0.5 \cdot I_{DSS}$ , Note 1	18	28		S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1\text{MHz}$	8.7	10.8	nF	
		800	1000	pF	
		300	375	pF	
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	<b>Resistive Switching Times</b> $V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 0.5 \cdot I_{DSS}$ $R_G = 1\Omega$ (External)	60		ns	
		35		ns	
		130		ns	
		24		ns	
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 0.5 \cdot I_{DSS}$	240		nC	
		56		nC	
		107		nC	
$R_{thJC}$			0.21	$^\circ\text{C}/\text{W}$	
$R_{thCS}$		0.05		$^\circ\text{C}/\text{W}$	

**Source-Drain Diode**
 $T_J = 25^\circ\text{C}$  unless otherwise specified

			Characteristic Values		
			Min.	Typ.	Max.
$I_s$	$V_{GS} = 0\text{V}$	25N90		25	A
		26N90		26	A
$I_{SM}$	Repetitive, pulse width limited by $T_{JM}$	25N90		100	A
		26N90		104	A
$V_{SD}$	$I_F = I_S$ , $V_{GS} = 0\text{V}$ , Note 1			1.5	V
$t_r$ $Q_{RM}$ $I_{RM}$	$I_F = I_S$ , $-di/dt = 100\text{A}/\mu\text{s}$ $V_R = 100\text{V}$		1.4	250	ns
			10		$\mu\text{C}$

Note 1: Pulse test,  $t \leq 300\mu\text{s}$ ; duty cycle,  $d \leq 2\%$ .

**SOT-227B Outline**


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	1.240	1.255	31.50	31.88
B	.307	.323	7.80	8.20
C	.161	.169	4.09	4.29
D	.161	.169	4.09	4.29
E	.161	.169	4.09	4.29
F	.587	.595	14.91	15.11
G	1.186	1.193	30.12	30.30
H	1.496	1.505	38.00	38.23
J	.460	.481	11.68	12.22
K	.351	.378	8.92	9.60
L	.030	.033	0.76	0.84
M	.496	.506	12.60	12.85
N	.990	1.001	25.15	25.42
O	.078	.084	1.98	2.13
P	.195	.235	4.95	5.97
Q	1.045	1.059	26.54	26.90
R	.155	.174	3.94	4.42
S	.186	.191	4.72	4.85
T	.968	.987	24.59	25.07
U	-.002	.004	-0.05	0.1

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338 B2  
4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2  
4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

Figure 1. Output Characteristics at 25°C

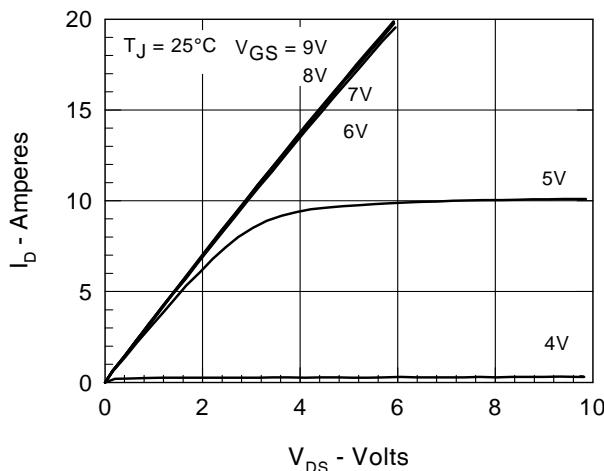


Figure 3.  $R_{DS(on)}$  normalized to 0.5  $I_{D25}$  value vs.  $I_D$

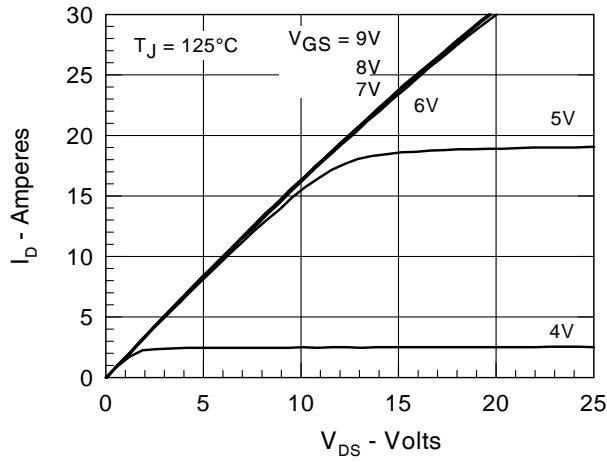


Figure 5.  $R_{DS(on)}$  normalized to 0.5  $I_{D25}$  value vs.  $I_D$

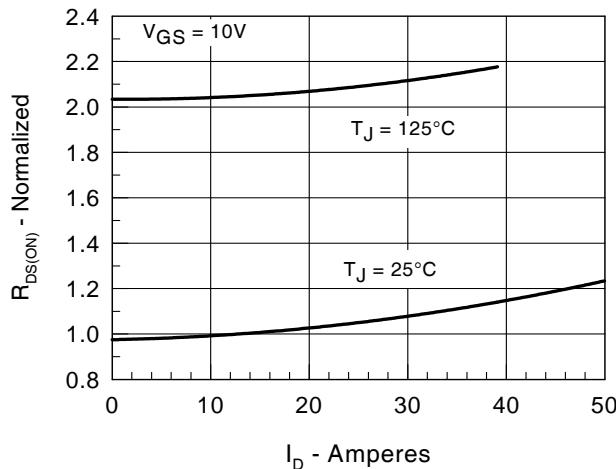


Figure 2. Extended Output Characteristics at 125°C

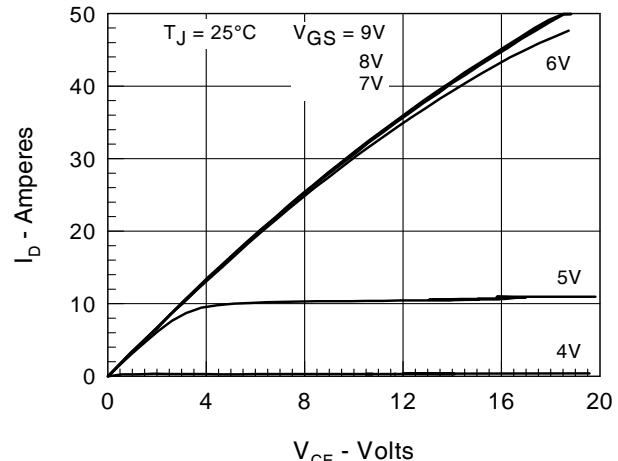


Figure 4. Admittance Curves

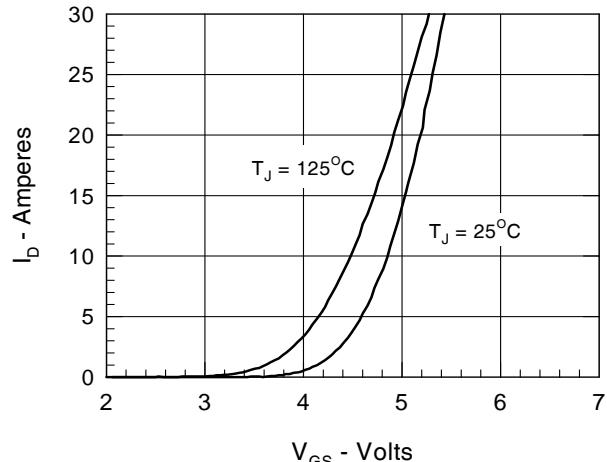


Fig. 6.  $R_{DS(on)}$  Normalized to 0.5  $I_{D25}$  Value vs. Junction Temperature

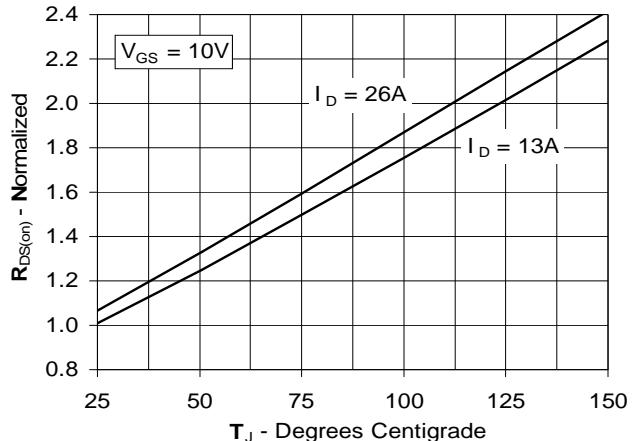


Figure 7. Gate Charge

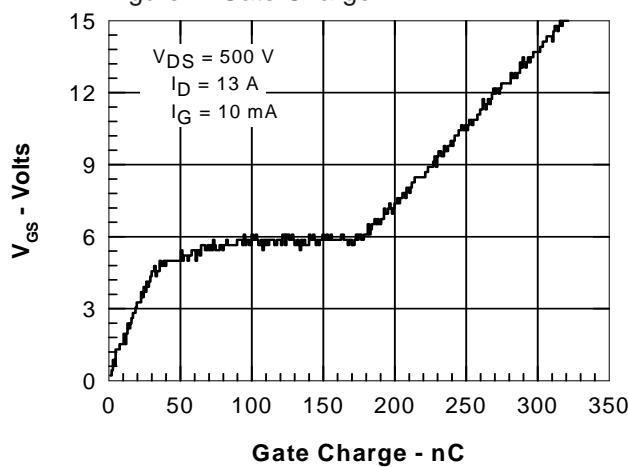


Figure 8. Capacitance Curves

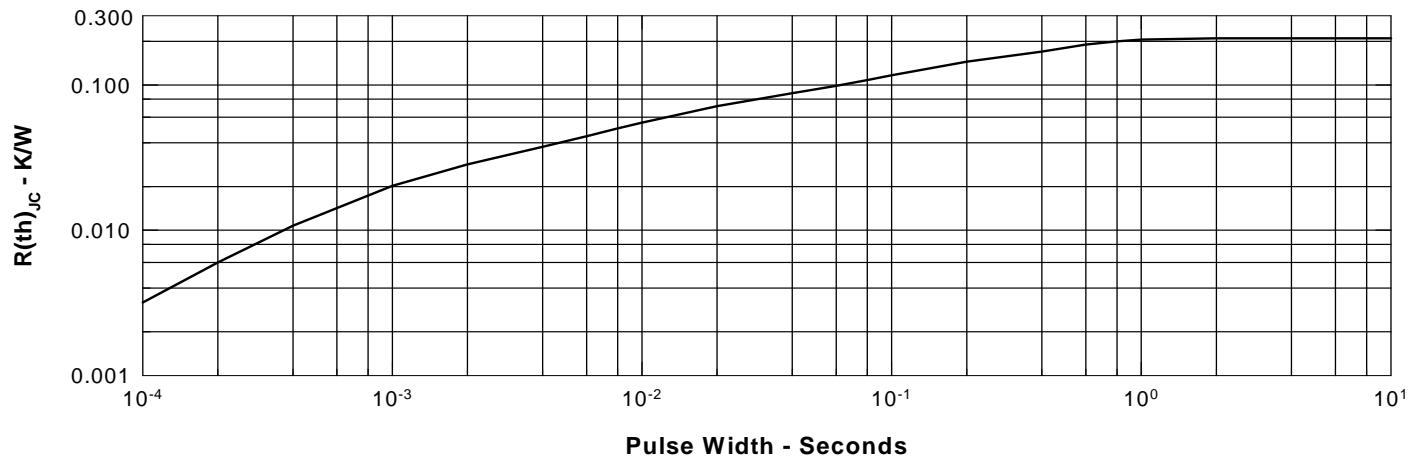
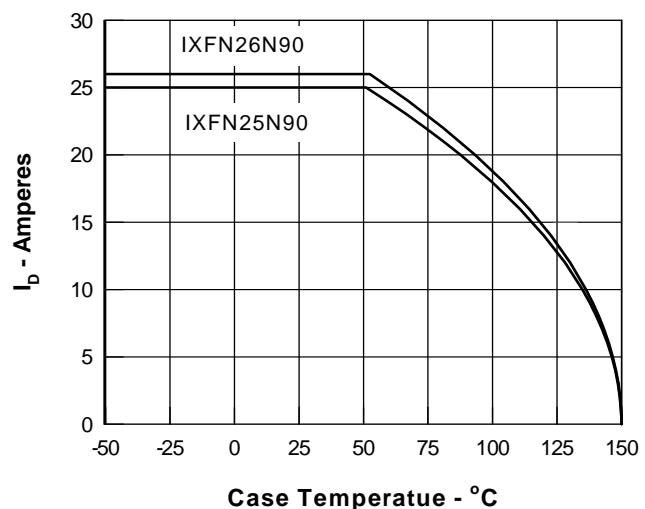
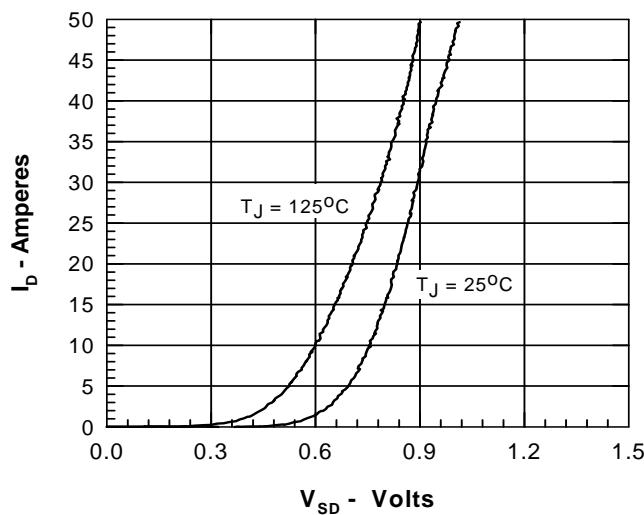
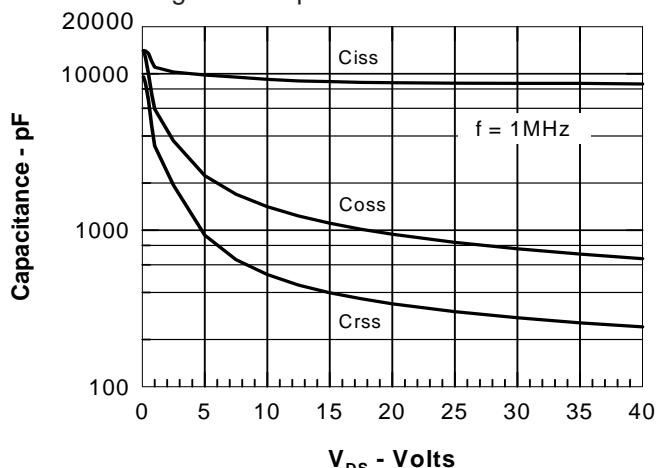


Figure 11. Transient Thermal Resistance

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